

STF26NM60N

N-channel 600 V, 0.135 Ω typ., 20 A MDmesh™ II Power MOSFET in a TO-220FP package

Datasheet - production data

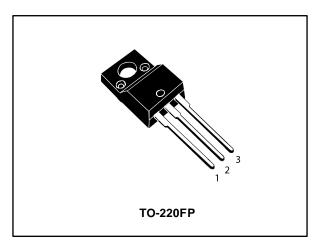
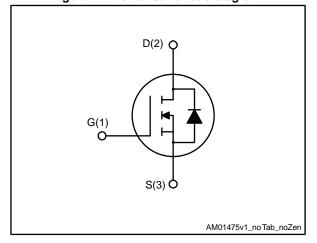


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max	ID
STF26NM60N	600 V	0.165 Ω	20 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packaging
STF26NM60N	26NM60N	TO-220FP	Tube

December 2016 DocID030178 Rev 1 1/13

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STF26NM60N Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage	600	V
V _{GS}	Gate-source voltage	±30	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	20	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	12.6	Α
I _{DM} (1)(2)	Drain current (pulsed)	80	Α
Ртот	Total dissipation at $T_C = 25$ °C	35	W
dv/dt (3)	Peak diode recovery voltage slope	15	V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink $(t=1\ s; T_C=25\ ^\circ C)$	2500	٧
T _{stg}	Storage temperature range	FF to 150	°C
Tj	Operating junction temperature range	-55 to 150	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	3.6	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AS}	Single pulse avalanche current (pulse width limited by T _{jmax})	6	Α
Eas	Single pulse avalanche energy (starting T _J =25 °C, I _D =I _{AR} , V _{DD} =50 V)	610	mJ

⁽¹⁾Limited by package.

⁽²⁾Pulse width limited by safe operating area.

 $^{^{(3)}}$ I_{SD} \leq 20 A, di/dt \leq 400 A/ μ s, V_{DS(peak)} \leq V(BR)DSS, V_{DD} \leq 80% V(BR)DSS

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0 V	600			V
	Zaro goto voltago drain	V _{GS} = 0 V, V _{DS} = 600 V			1	
IDSS	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{C} = 125 \text{ °C} ^{(1)}$			100	μΑ
Igss	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±0.1	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 10 A		0.135	0.165	Ω

Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	1800	ı	pF
Coss	Output capacitance	$V_{DS} = 50 \text{ V}, f = 1 \text{ MHz},$	-	115	1	pF
C _{rss}	Reverse transfer capacitance	V _G S = 0 V	-	6	ı	pF
Coss eq. (1)	Equivalent output capacitance	V _{GS} = 0 V, V _{DS} = 0 to 480 V	1	310	ı	pF
Qg	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 20 \text{ A},$	-	60	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	8.5	-	nC
Q_{gd}	Gate-drain charge	(see Figure 14: "Test circuit for gate charge behavior")	-	30	1	nC
Rg	Gate input resistance	f=1 MHz, I _D =0 A	-	2.8	1	Ω

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 10 \text{ A},$	ı	13	1	ns
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 13: "Test circuit for	-	25	-	ns
t _{d(off)}	Turn-off delay time	resistive load switching times"	-	85	-	ns
t _f	Fall time	and Figure 18: "Switching time waveform")	1	50	1	ns

 $^{^{(1)}}$ Defined by design, not subject to production test.

 $^{^{(1)}}C_{oss~eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} ⁽¹⁾	Source-drain current		-		20	Α
I _{SDM} ⁽²⁾	Source-drain current (pulsed)		-		80	Α
V _{SD} ⁽³⁾	Forward on voltage	I _{SD} = 20 A, V _{GS} = 0 V	-		1.5	V
t _{rr}	Reverse recovery time	I _{SD} = 20 A, di/dt = 100 A/μs	-	370		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}$	-	5.8		μC
I _{RRM}	Reverse recovery current	(see Figure 15: "Test circuit for inductive load switching and diode recovery times")	-	31.6		Α
t _{rr}	Reverse recovery time	I _{SD} = 20 A, di/dt = 100 A/μs	-	450		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 ^{\circ}\text{C} \text{ (see}$	-	7.5		μC
I _{RRM}	Reverse recovery current	Figure 15: "Test circuit for inductive load switching and diode recovery times")	-	32.5		А

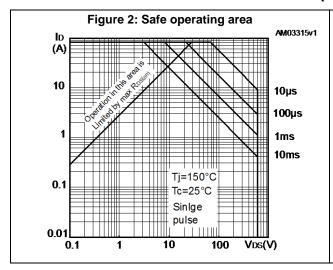
Notes:

⁽¹⁾Pulse width limited by package.

 $[\]ensuremath{^{(2)}}\mbox{Pulse}$ width limited by safe operating area.

 $^{^{(3)}\}text{Pulsed:}$ pulse duration = 300 $\mu\text{s,}$ duty cycle 1.5%

2.1 Electrical characteristics (curves)



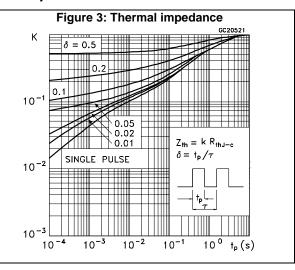
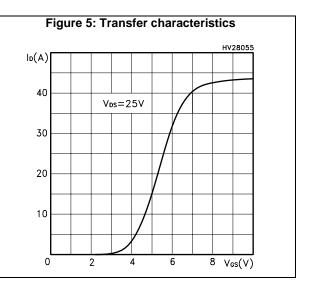
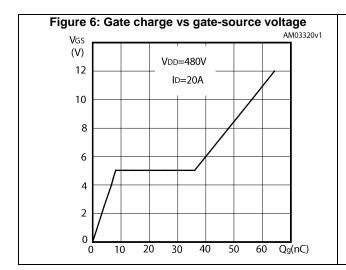
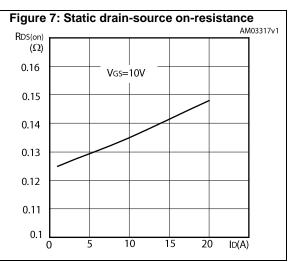


Figure 4: Output characteristics lo(A) V_{GS}=10V 8٧ 40 9٧ 7٧ 30 6٧ 20 5٧ 10 4V Vps(V) 15 20

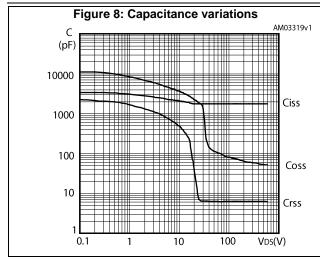






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STF26NM60N Electrical characteristics



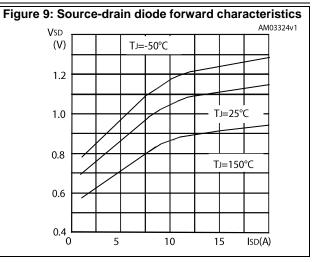
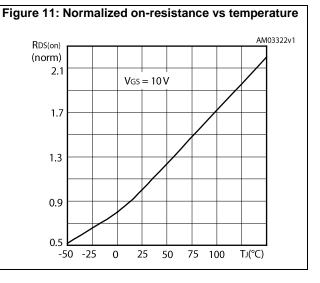
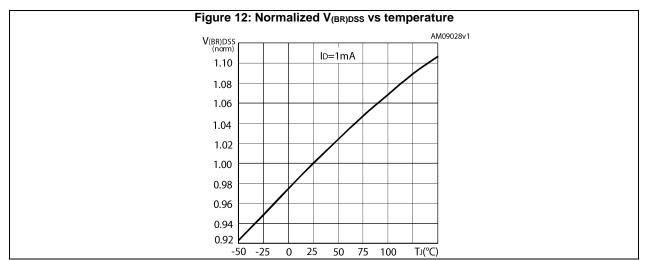


Figure 10: Normalized gate threshold voltage vs temperature AM03321v1 $V_{GS(th)}$ (norm) 1.1 $ID = 250 \mu A$ 1.0 0.9 0.8 0.7 -50 -25 0 50 75 25 100 T)(°C)







Test circuits STF26NM60N

3 Test circuits

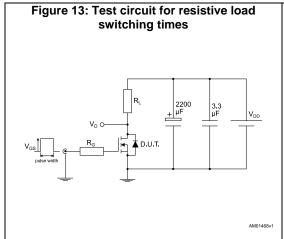


Figure 14: Test circuit for gate charge behavior

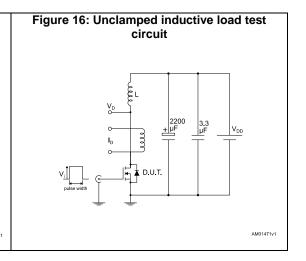
12 V 47 kΩ 100 nF 1 kΩ

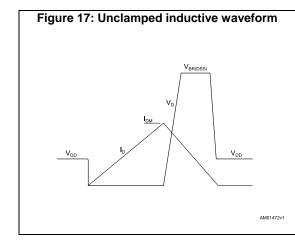
Vos 1 kΩ 1 kΩ

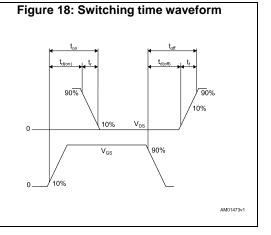
Vos 1 kΩ 1 kΩ

AM01466y1

Figure 15: Test circuit for inductive load switching and diode recovery times







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STF26NM60N Package information

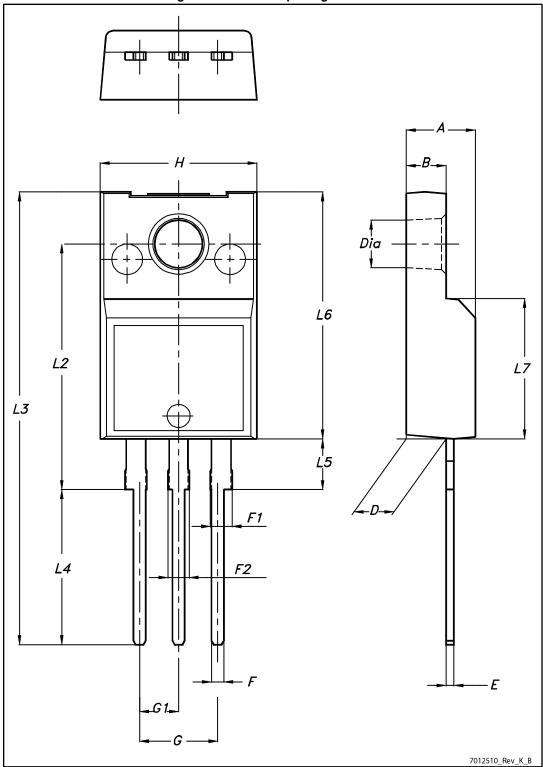
4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



4.1 TO-220FP package information

Figure 19: TO-220FP package outline



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Table 9: TO-220FP package mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
Α	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2



Revision history STF26NM60N

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
13-Dec-2016	1	First release. Part number previously included in datasheet DocID15642

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